

<b>Notice of References Cited</b>	Application/Control No. 10/801,872		Applicant(s)/Patent Under Reexamination MEEK ET AL.	
	Examiner Benny Q. Tieu		Art Unit 2614	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,574,780	11-1996	Andruska et al.	379/221.09
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	K	US-			
	L	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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